



## 九州工業大学における宇宙機帯電放電の研究

九州工業大学 宇宙環境技術ラボラトリー

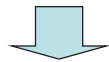
豊田和弘 趙孟佑

### 放電事故



1997年 静止軌道衛星Tempo-2

発電電力の15%が低下



世界中の研究機関が調査を開始

Tempo-2



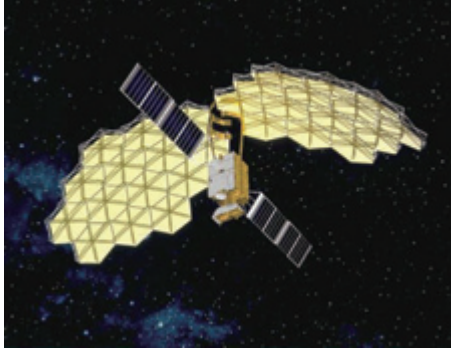
太陽電池アレイと宇宙プラズマと  
の相互作用により放電が発生

持続放電 → アレイ回路の短絡 → 電力損失



## ETS-VIII

### Development of a solar array for ETS-VIII



#### Engineering Test Satellite VIII (ETS-VIII)

- Launch in 2006
- Geosynchronous Orbit(GEO)
- **110V at 2.64A** electric power generation
- **Silicone** solar cell

#### Purpose of the ground tests

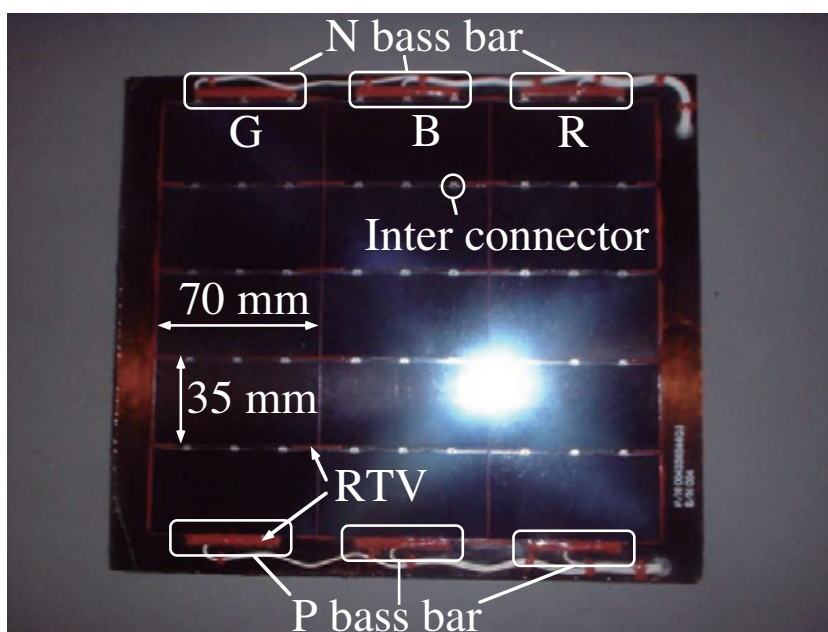
Determine the design of coupon preventing the sustained arcs

帯電放電試験 2001年～

3



### Solar array coupons



We used 3 coupons.

Thick coupon×2  
(Case1～3)

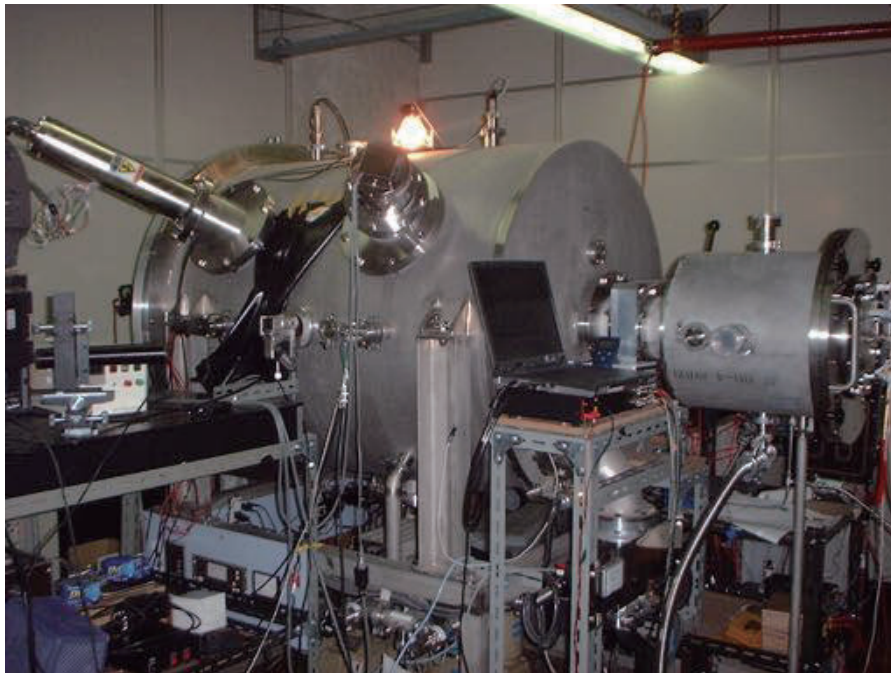
Thin coupon×1  
(Case4)

5 ×3 Si cell with

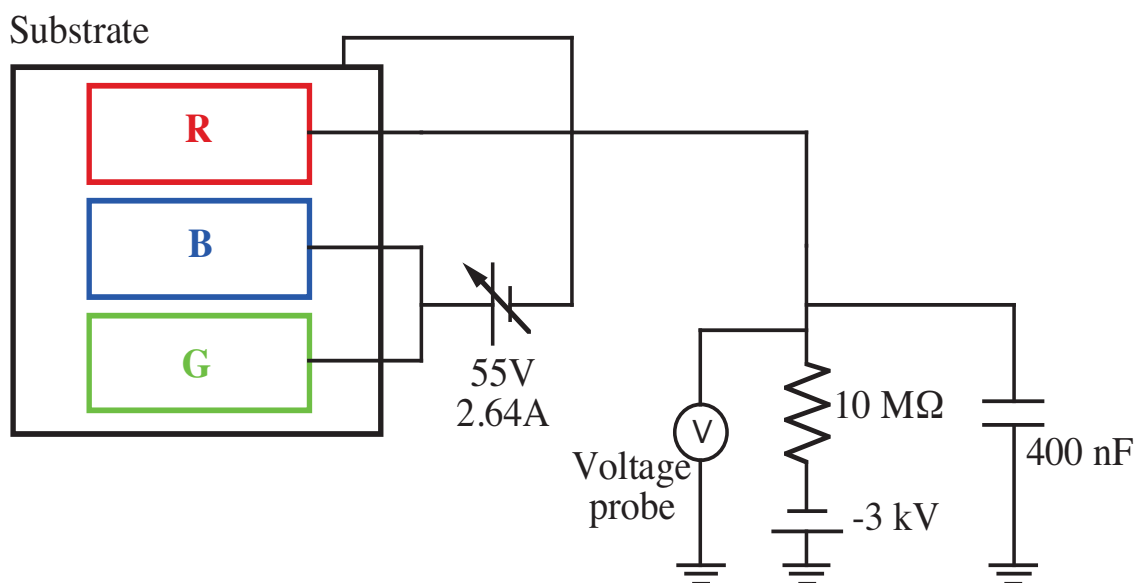
**IBF**  
IBF: Integrated Bypass Function

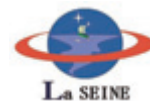


## Experimental facility

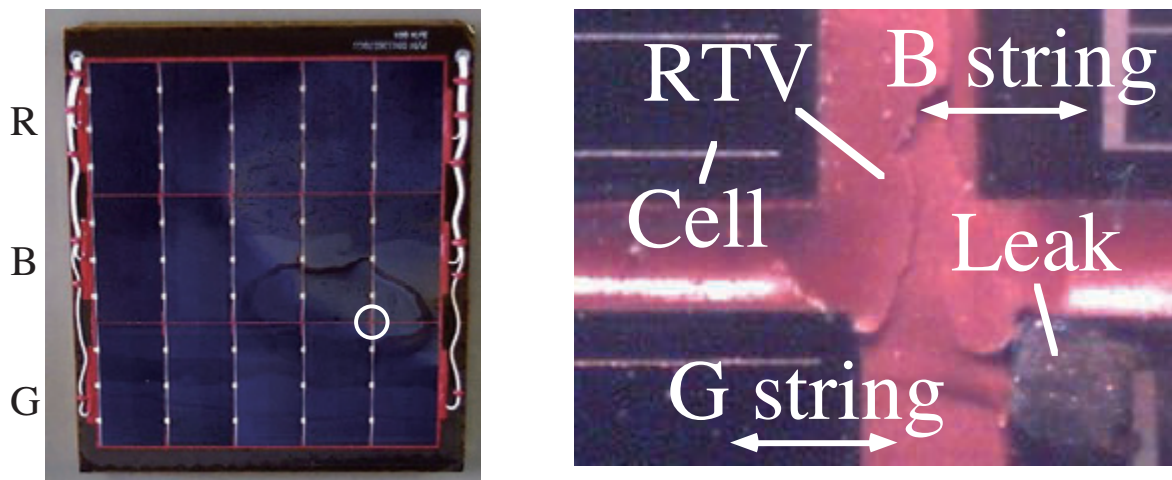


## Experimental circuit





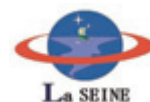
## セルの電流リーク箇所



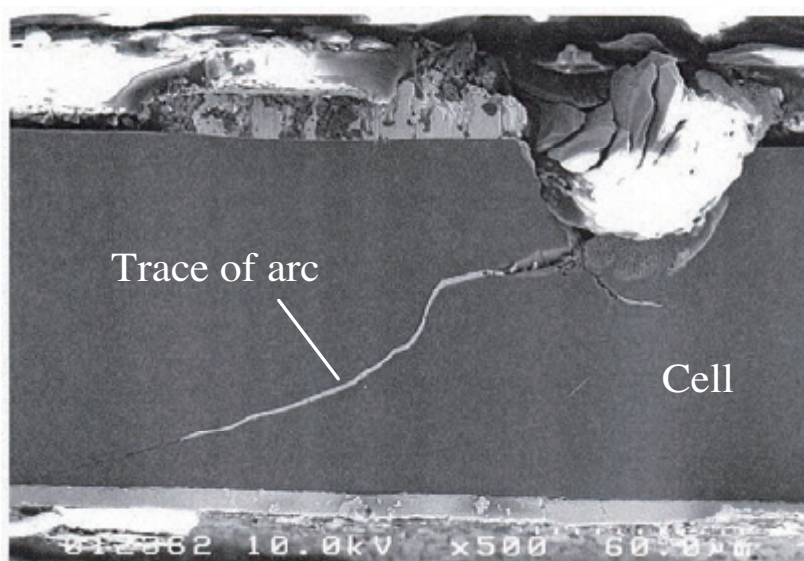
Current leaking point was identified by IR-OBIRCH analysis

IR-OBIRCH (Optical Beam Induced Resistance Change)

7



## セル断面



**Silver was found on the trace of arc by EDX**

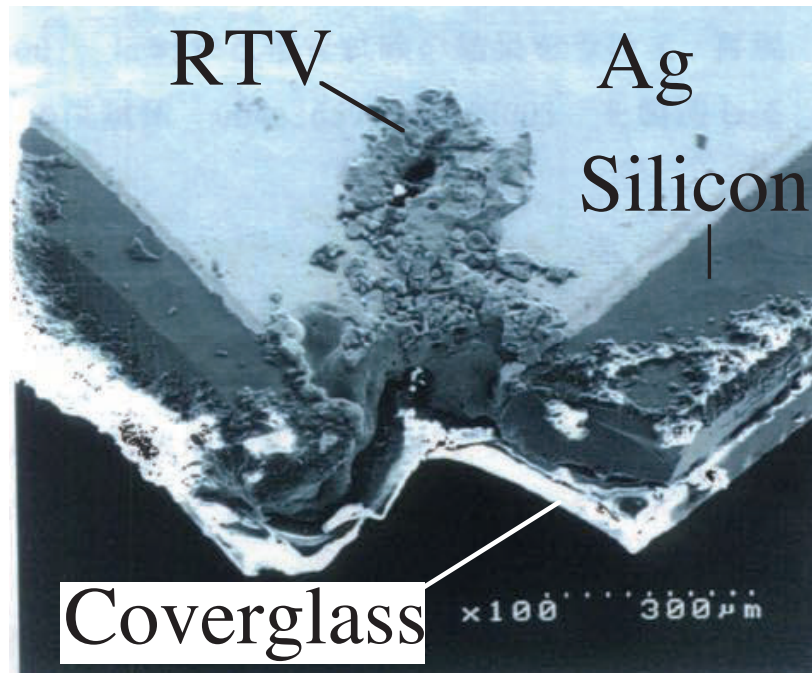
EDX : Energy Dispersive X-ray Spectroscopy

8





## セル裏面

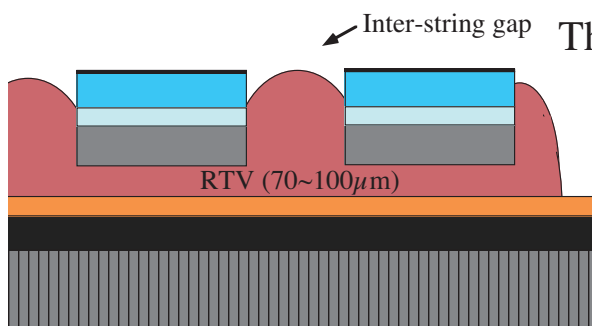
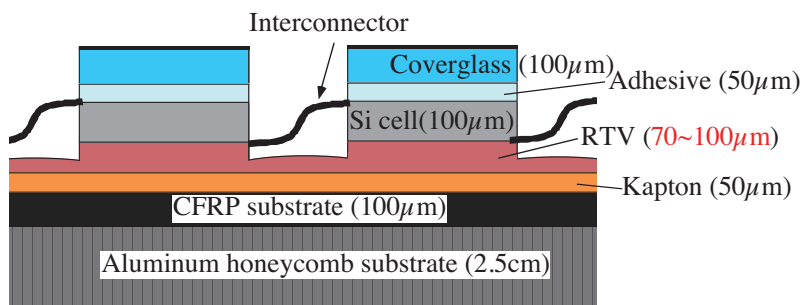


9

## Flight design of coupon for ETS VIII



- No sustained arcs during 30 hours (about 500 arcs)



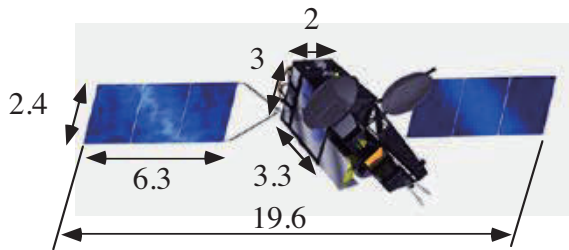
The amount of RTV should be minimum

To keep insulation between both  
inter-string gaps and  
string-substrate

10



# WINDS



## Wideband InterNetworking engineering test and Demonstration Satellite (WINDS)

- Launch in 2008
- Geosynchronous Orbit(GEO)
- Electric power generation: 5.2 kW (**50V at 0.6A**)
- **Multi-junction** solar cell

11



## Test procedure

Measure the threshold of potential difference  $\Delta V_{min}$  for arcing



Calculate the charge stored in the coverglass



Perform ESD tests using 3 coupons for 20 hours



Select one coupon

Perform ESD tests using the selected coupon for the  $t_{IG}$  totally



Determine the flight design

Calculate the time ( $t_{IG}$ ) on IG condition over  $\Delta V_{min}$  and estimate the number of arcs

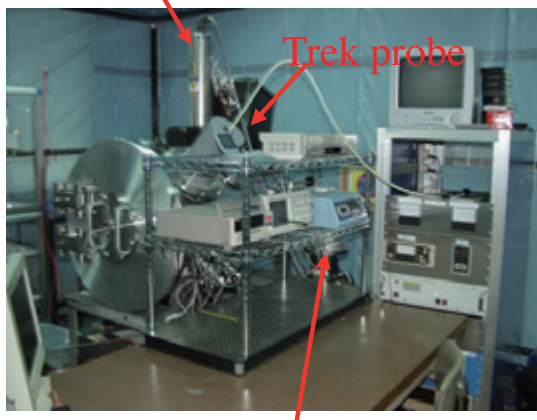


12

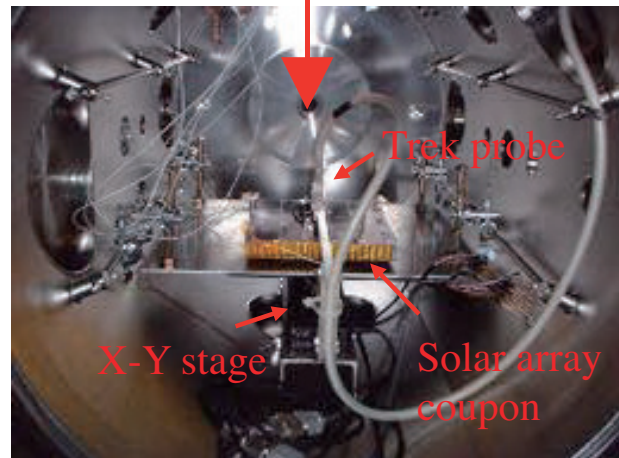


## Experimental facility

Electron beam gun (max30kV)



X-Y stage controller



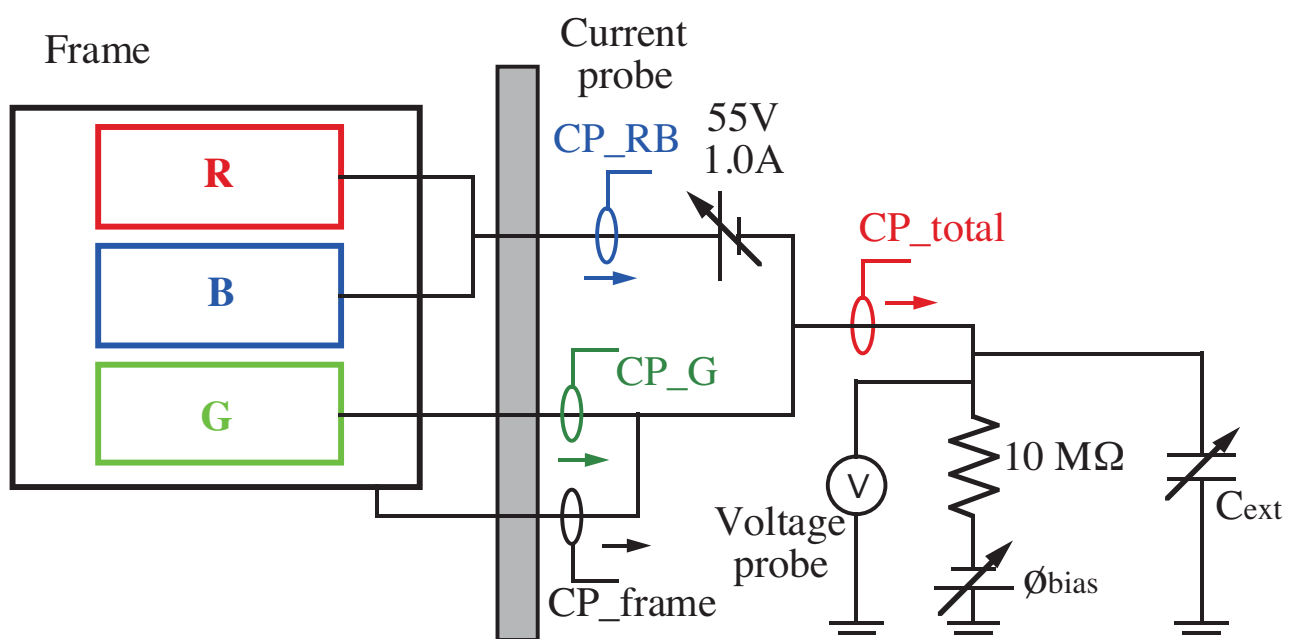
**Vacuum chamber:** 0.6m in diameter and 0.9m in length up to  $3 \times 10^{-7}$  Torr

**Equipment:** Electron beam gun, Trek probe, Plasma source, Video analysis system, XY stage, Baking system, UV source

13



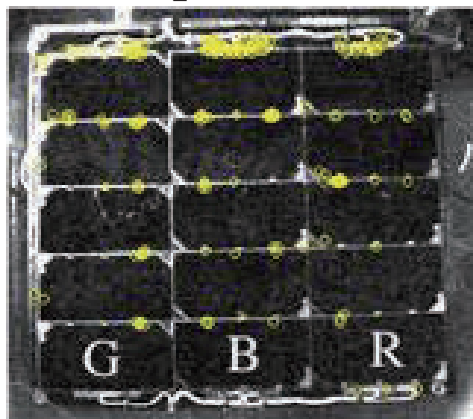
## Experimental circuit



14

## Effect of bus bar coating

### Coupon 3



- No sustained arcs
- No difference at arc positions

Select coupon 3 as a flight model



65 hour test

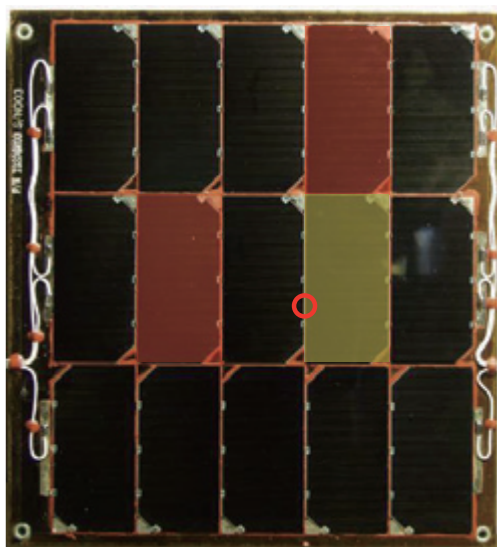
(60 hours from NASCAP calculation)

Case	Position	N <sub>arc</sub>	I <sub>ave</sub> , A	I <sub>std</sub> , A	Q <sub>ave</sub> , mC	Q <sub>std</sub> , mC
10	Bus bar	78	122	36	1.23	0.08
10	IC	71	128	34	1.24	0.09
11	Bus bar	43	91	37	0.79	0.05
11	IC	66	88	24	0.75	0.04

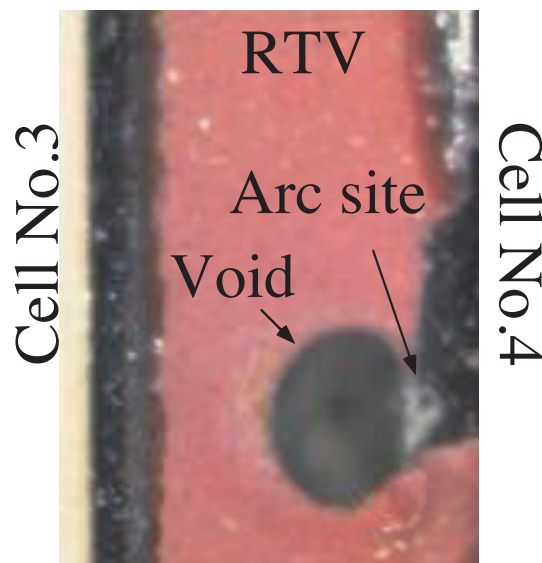
15

## Degraded cells

### Coupon 2



3 cells were degraded



IR-OBIRCH method

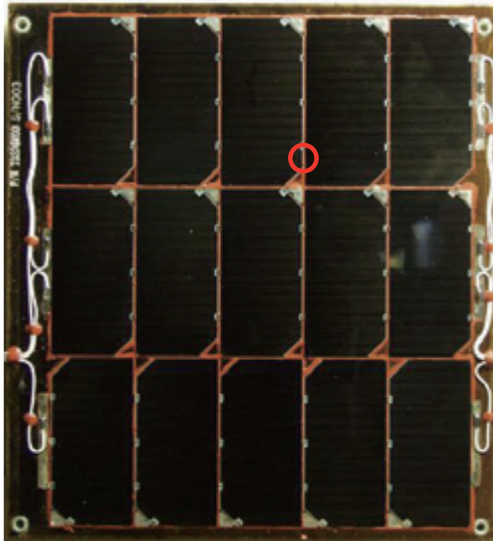
16



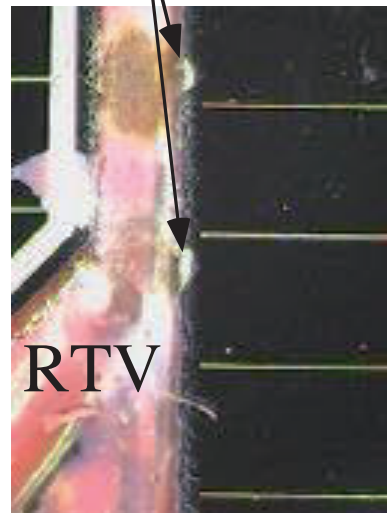


## Cell degradation

Coupon 3



Arc site



**Cell edge arc can destroy the cell**

17

## Conclusions



- To suppress the inter-string sustained arc, the gap between strings is grouted with RTV
- To suppress the string-substrate sustained arc, the RTV layer between the cells and the Kapton sheet is specified as 100  $\mu\text{m}$  and the RTV layer leaks out at the cell gap in the direction of series connection
- There is no coating of bus bar with RTV
- To avoid trigger arcs at the cell edges, we give the best effort to fill in the voids of RTV by additional RTV

18

## WINDS打ち上げ 2008.2.23



19

## ADEOS II



- みどり2号  
極軌道衛星

2003年10月25日  
発電電力が6kWから1kW  
に低下



©JAXA

熱制御材の帯電



ケーブルと放電

20



## 検証試験



21

## 宇宙環境技術研究センター



2004年12月 設立

宇宙環境に耐えるモノ作り技術の開発

Laboratory of Spacecraft Environmental Interaction Engineering

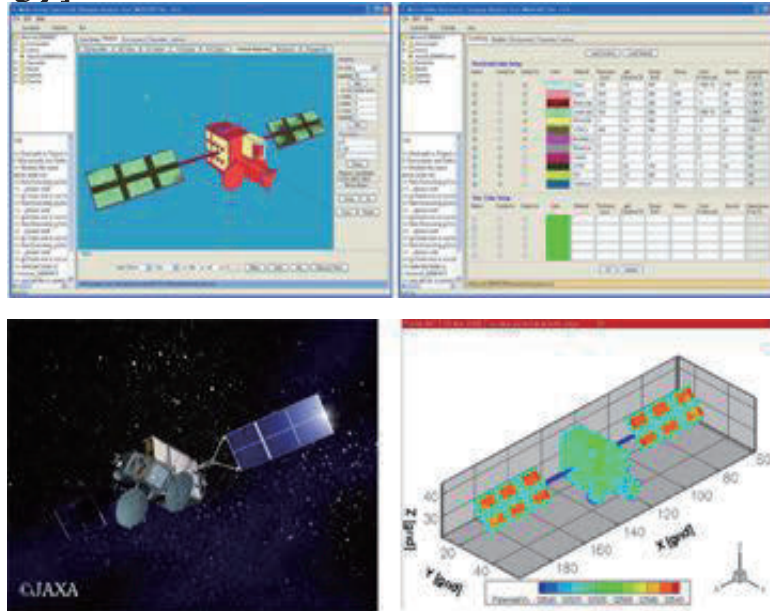


22



## MUSCAT

- **Multi-Utility Spacecraft Charging Analysis Tool**
- **GEO, PEO, LEO**
- **2007年3月**



23

## ISO-11221 "Space systems -- Space solar panels -- Spacecraft charging induced electrostatic discharge test methods"



- **Measure discharge threshold voltage**
- **Estimate the number of discharge with charging analysis program**
- **Calculate external capacitance in test circuit**
- **Perform ESD test on test coupon with desired number of discharge**
- **Confirm there is no sustained arc and no degradation of solar cell**
- **Estimate power degradation due to cell degradation**
- **Decide design of solar array circuit**
- **Reflect test result in spacecraft system design**

24



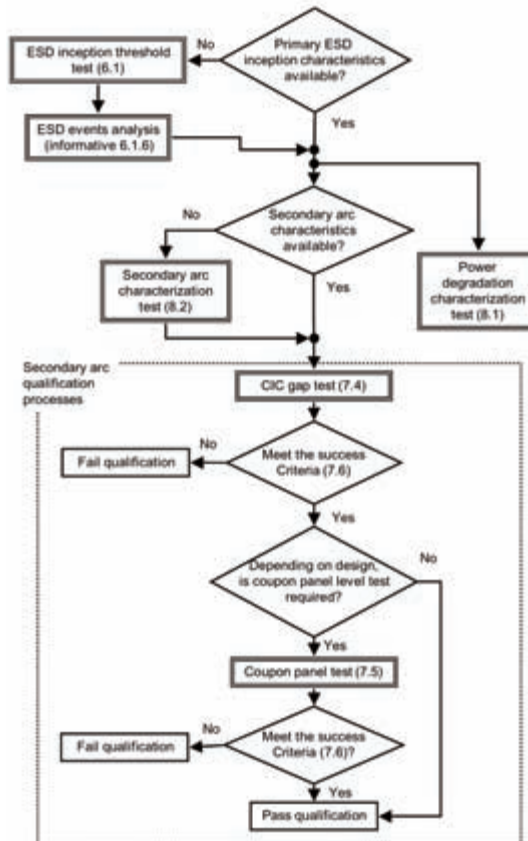
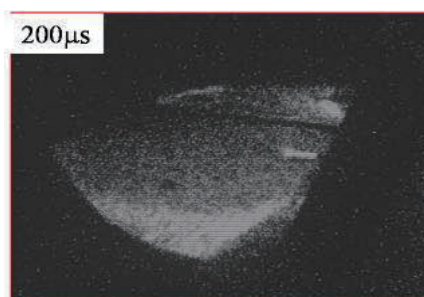
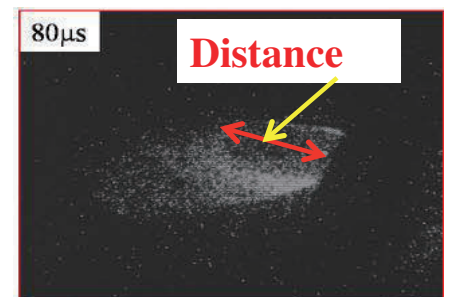
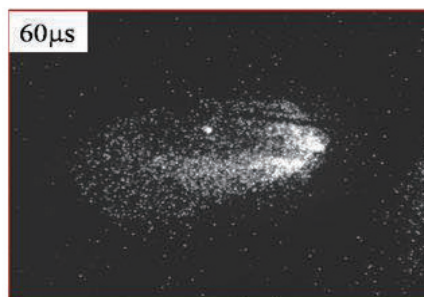


Figure 2: Logic flow of ESD tests

25

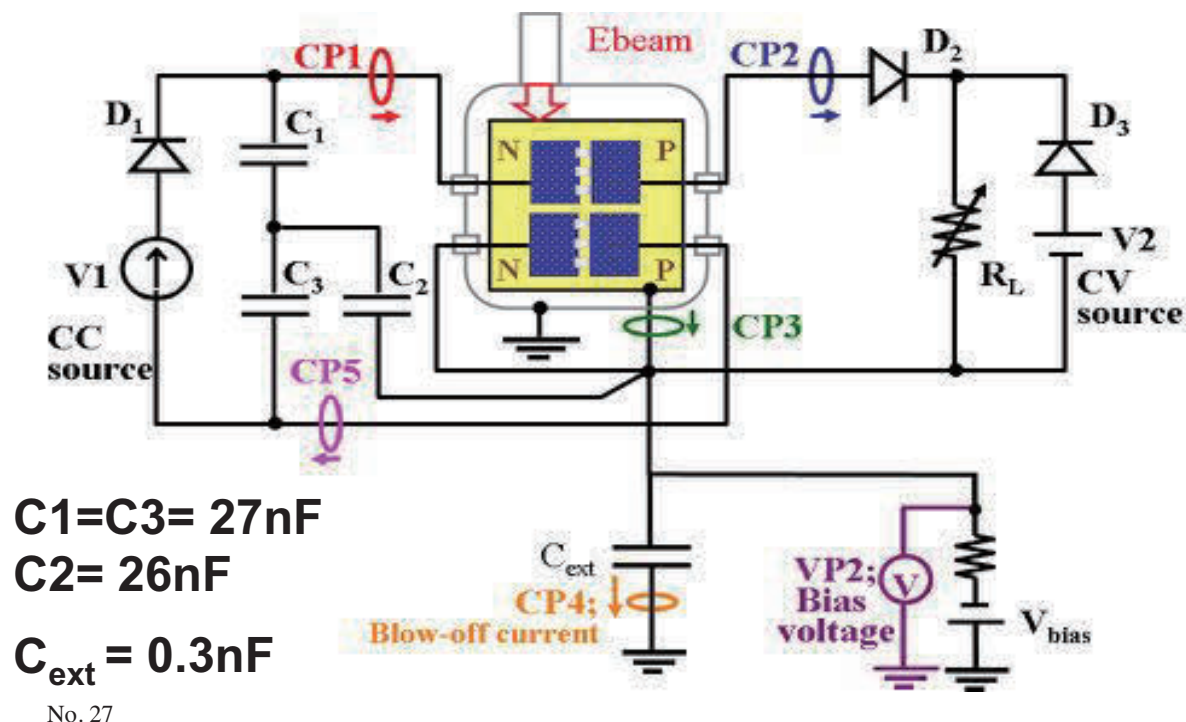
## 沿面放電

Velocity  $\sim 10^4$  m/s  
Radius 3m

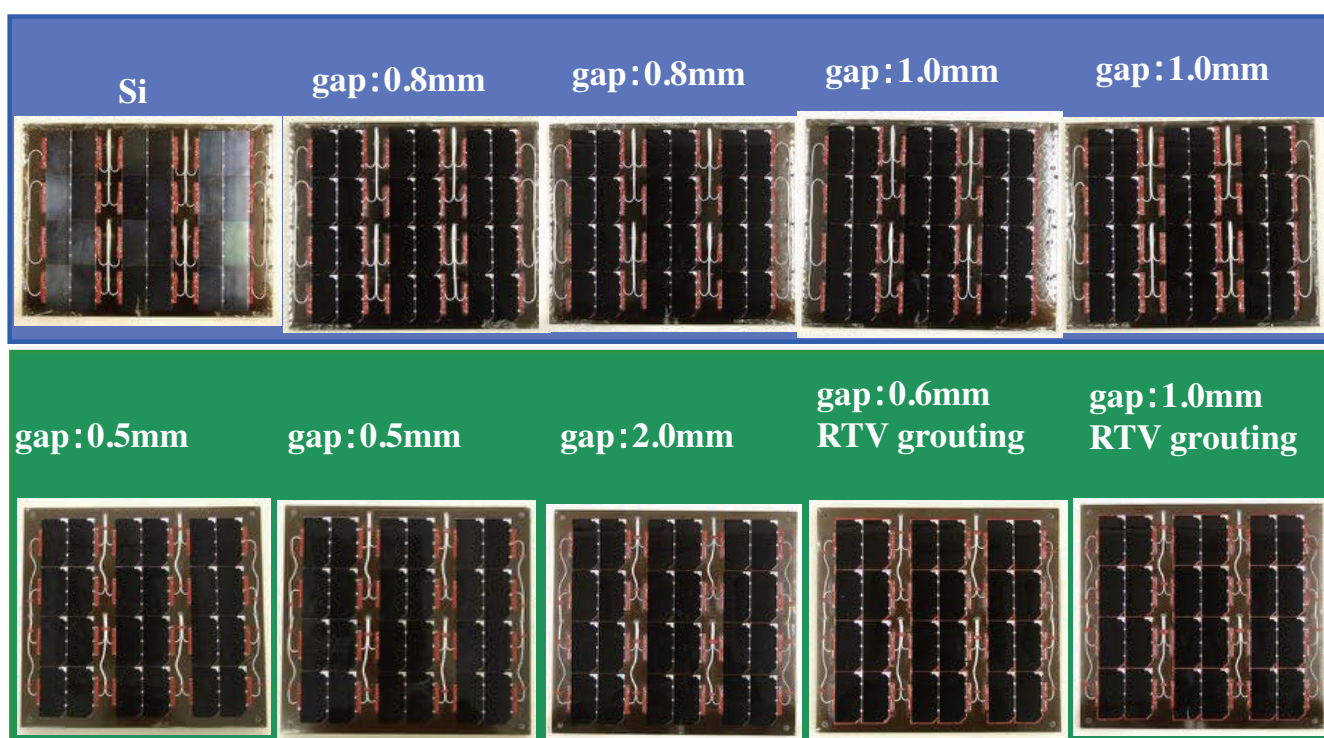




## 持続放電回路

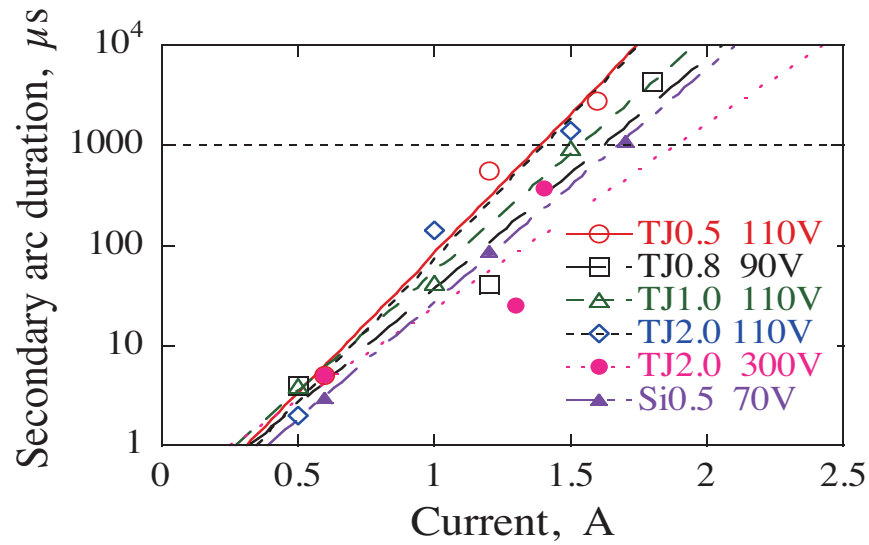


## 帯電・放電設計標準





## TSA duration



- TSA duration depends on current value
- The duration of 1ms corresponds to PSA threshold

29



## TJ 0.5mm

$V_{st}$ , V	$I_{st}$ , A			
	0.5	1.0	1.5	2.0
30	No secondary arc up to 4A			
50	7μs (0.7A)	28μs	4534μs (1.7A)	
70	4μs (0.6A)	250μs (1.2A)	7747μs (1.8A)	
90	54μs (0.5A)	231μs (1.2A)		
110	5μs (0.6A)	552μs (1.2A)	2750μs (1.6A)	
	PA	NSA	TSA	PSA

30



**TJ 0.8mm**

$V_{st}, V$	$I_{st}, A$			
	0.5	1.0	1.5	2.0
30	No secondary arc up to 4A			
50		47 $\mu s$	4086 $\mu s$ (1.7A)	
70	7 $\mu s$ (0.7A)	209 $\mu s$ (1.2A)		
90	4 $\mu s$	41 $\mu s$ (1.2A)	4384 $\mu s$ (1.8A)	
110	3 $\mu s$ (0.6A)	179 $\mu s$ (1.2A)	7408 $\mu s$ (1.8A)	

**PA**
**NSA**
**TSA**
**PSA**

31



## TJ 1.0mm

$V_{st}, V$	$I_{st}, A$			
	0.5	1.0	1.5	2.0
30	No secondary arc up to 4A			
50		12 $\mu s$	1126 $\mu s$	4433 $\mu s$
70	3 $\mu s$	25 $\mu s$	1225 $\mu s$	
90	3 $\mu s$	7 $\mu s$ (0.9A)	415 $\mu s$ (1.3A)	
110	4 $\mu s$	42 $\mu s$	943 $\mu s$	

**PA**
**NSA**
**TSA**
**PSA**

32



## TJ 2.0mm

$V_{st}$ , V	$I_{st}$ , A			
	0.5	1.0	1.5	2.0
50	No secondary arc up to 4A			
70	7 $\mu$ s			
110	2 $\mu$ s	140 $\mu$ s	1400 $\mu$ s	3900 $\mu$ s
200	3 $\mu$ s (0.7A)	110 $\mu$ s (1.1A)	60 $\mu$ s (1.3A)	
300	5 $\mu$ s (0.6A)	25 $\mu$ s (1.3A)	370 $\mu$ s (1.4A)	

PA

NSA

TSA

PSA

33

## Si 0.5mm



$V_{st}$ , V	$I_{st}$ , A			
	0.5	1.0	1.5	2.0
30				
50	PA	PA	PA	PA
70	3 $\mu$ s (0.6A)	88 $\mu$ s (1.2A)	1098 $\mu$ s (1.7A)	
90				
110	4 $\mu$ s (0.6A)	233 $\mu$ s (1.2A)	727 $\mu$ s (1.7A)	

PA

NSA

TSA

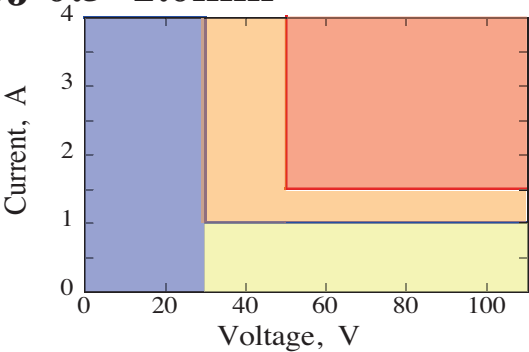
PSA

34

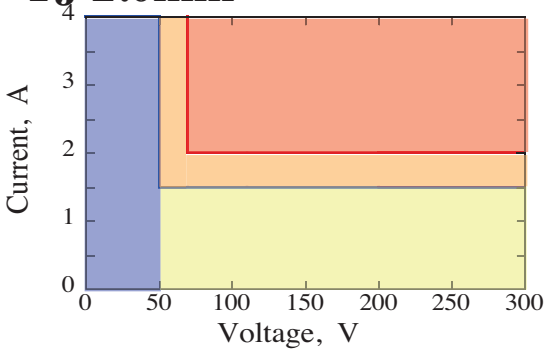


VI map

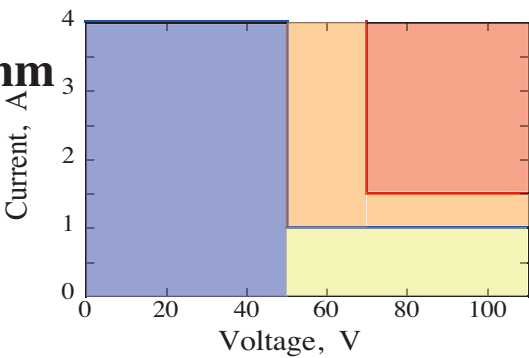
TJ 0.5~1.0mm



TJ 2.0mm



Si 0.5mm



Safe

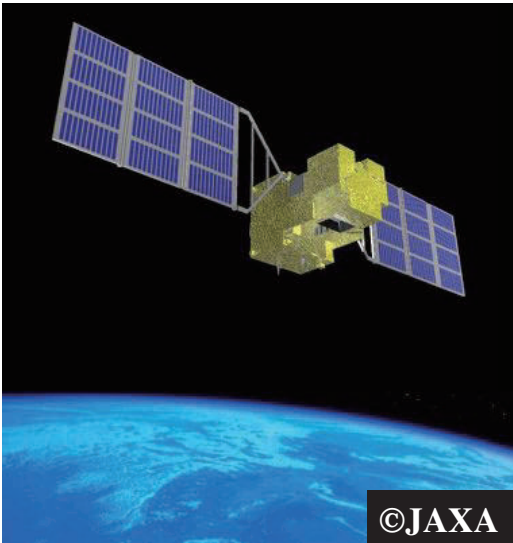
Caution

Danger

Prohibition 35



GOSAT

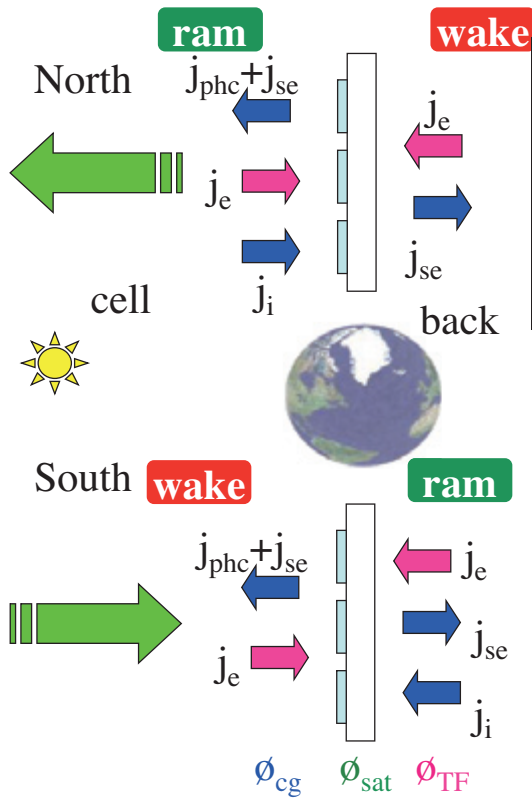


Item	Characteristics
Launch vehicle	H-IIA
Launch	2009.1.23
Launch site	Tanegashima Space Center
Orbit	666km Sun-synchronous inclination angle 98 degree 13:00 local time (3 day cycle)
Weight	1,750kg at launch
Generated electric power	More than 3.77kW (EOL)
Lifetime	5 years
Deployed dimension	3.7m(H) x 13.7m(W) x 2.0m(D)





## Charging mode

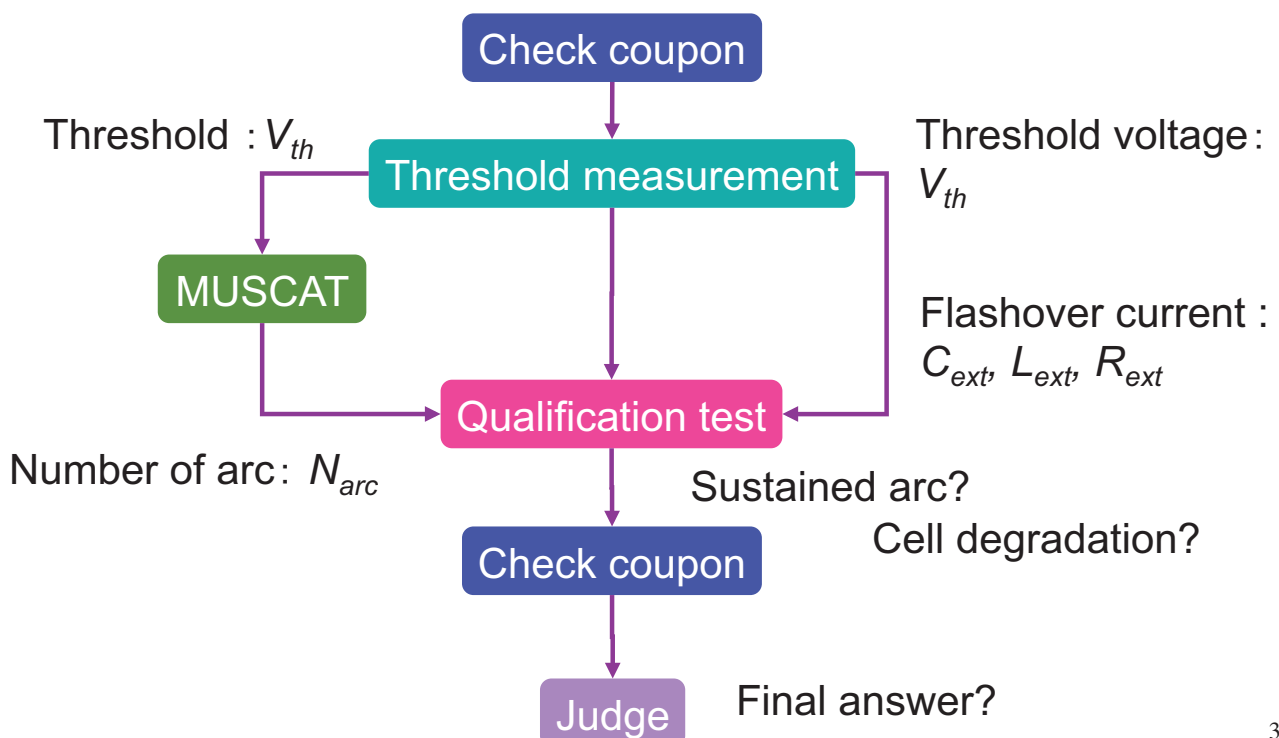


SAP	plasma	$\phi_{sat}$	$\phi_{dielec}$	Condition
cell	ram	N	0	Plasma IG
back	wake	N	$> \phi_{sat}$	Beam IG
		0 or N	$< \phi_{sat}$	Beam NG

SAP	plasma	$\phi_{sat}$	$\phi_{dielec}$	Condition
cell	wake	N	$> \phi_{sat}$	Beam IG
		0 or N	$< \phi_{sat}$	Beam NG
back	ram	N	0	Plasma IG

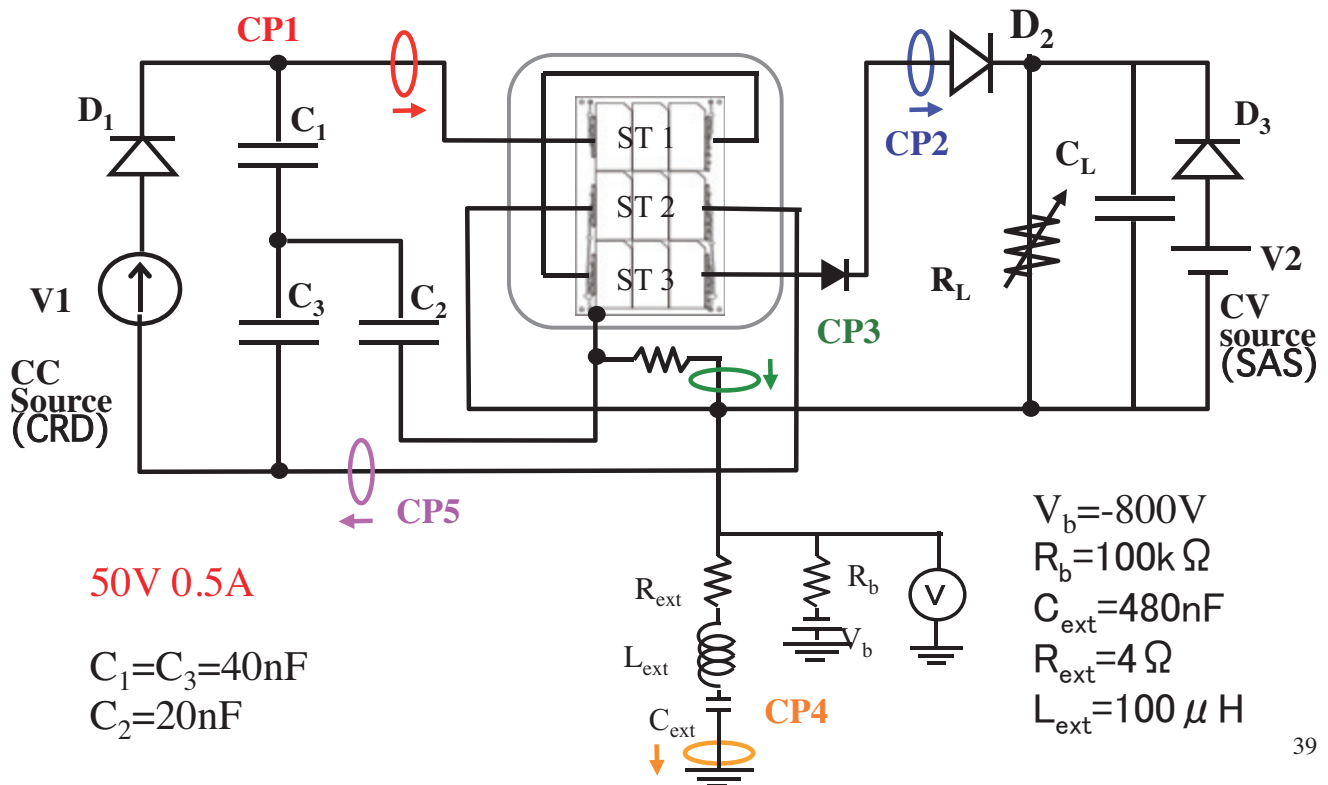
37

## Test procedure



38

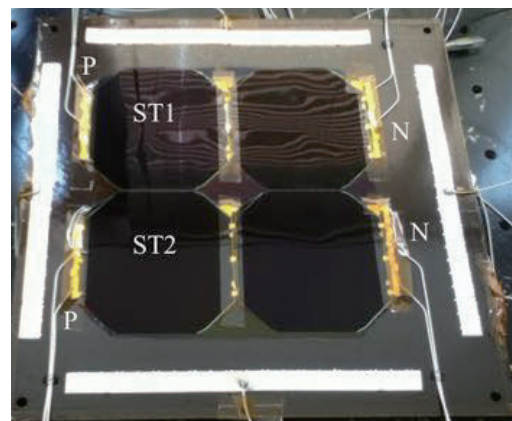
## Experimental circuit: plasma IG EOL



39

## 商用衛星

- Large solar cell
  - need ground ESD testing before launch



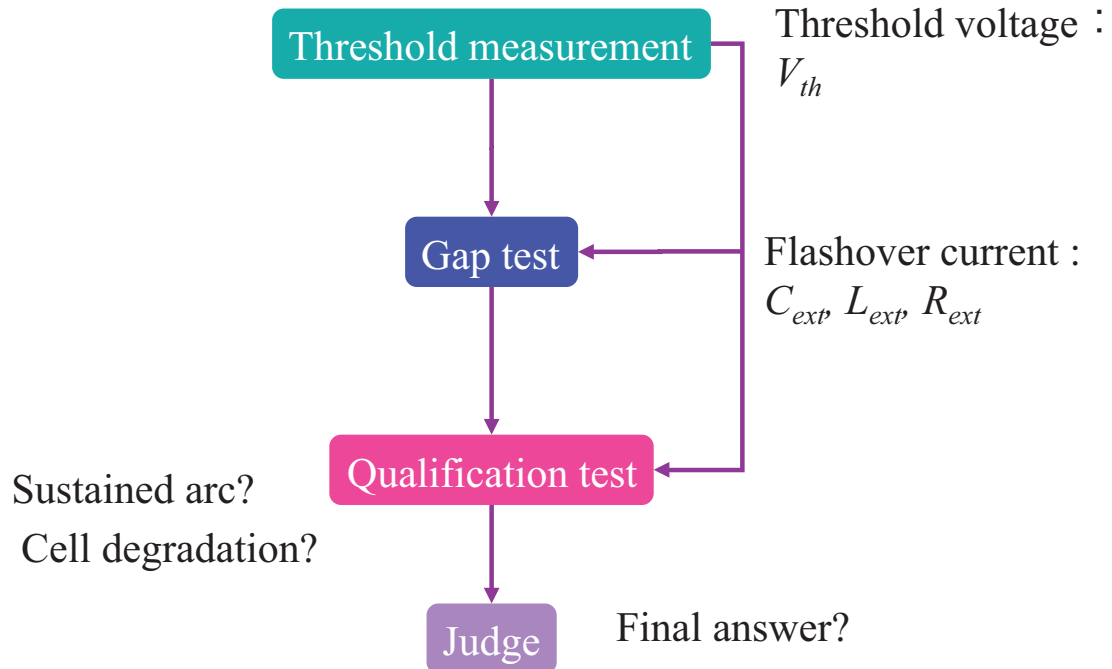
- ISO11221
  - Confirm no sustained arc
  - Measure cell degradation

40



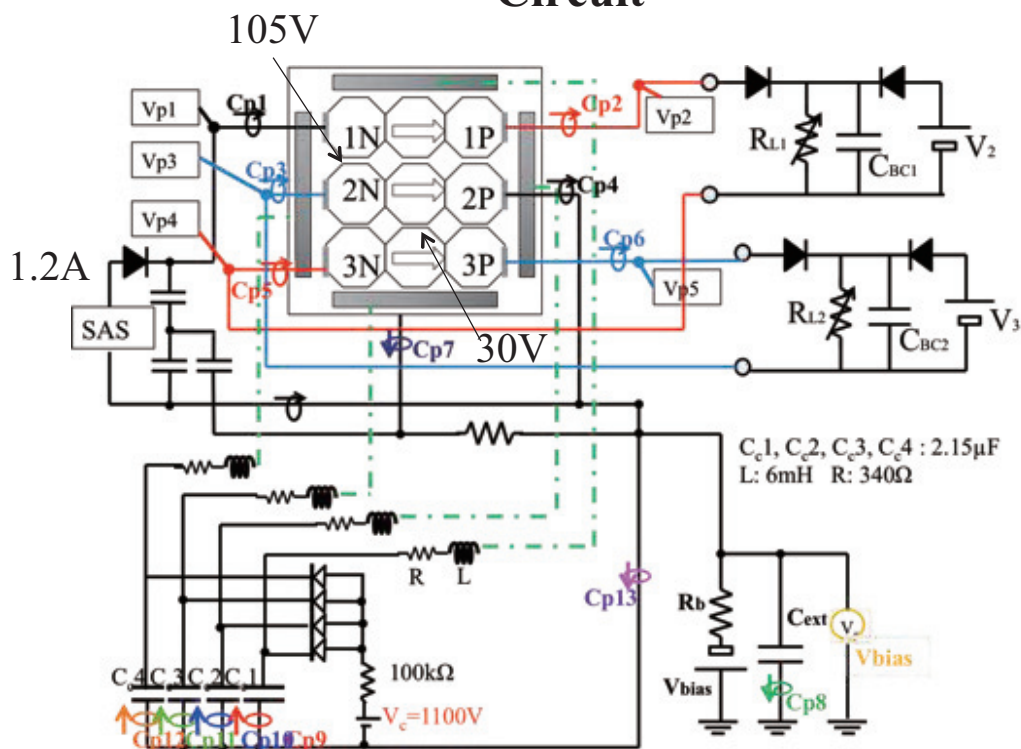
## Test procedure

ISO11221



41

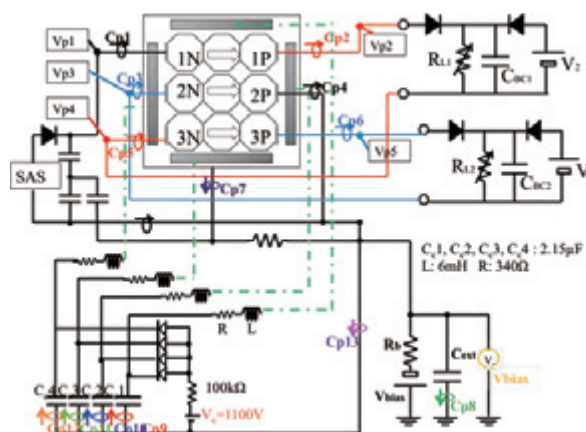
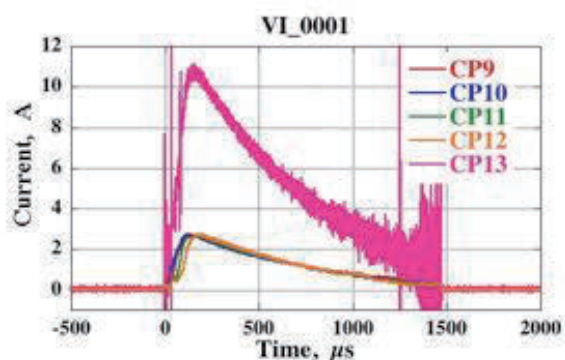
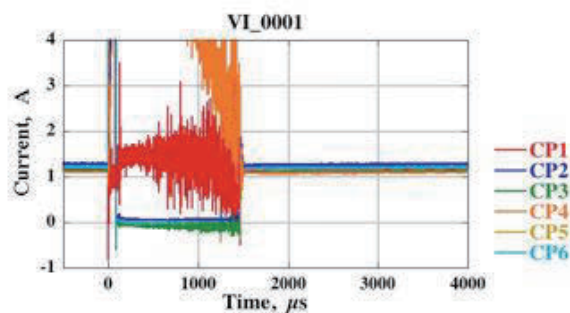
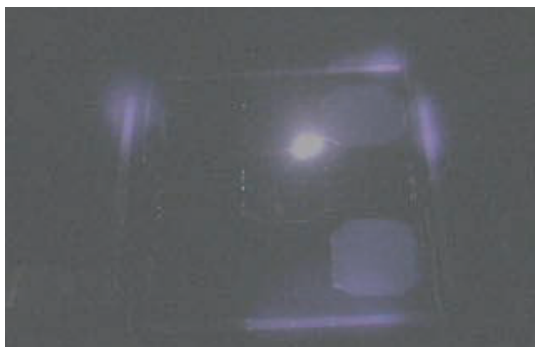
## Circuit



42



## Secondary arc in wide gap



43

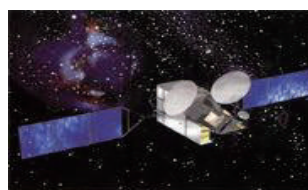
## 衛星地上帯電放電試験(1999年より)



はやぶさ(2003)



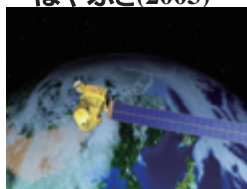
きく8号 (2006)



きずな(2008)



ひまわり7号(2006)

みどり2 (2003)  
原因究明作業

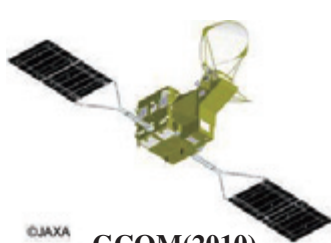
だいち(2006)



きらり(2005)



いぶき(2008)



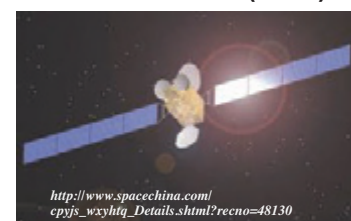
GCOM(2010)



インド



アメリカ

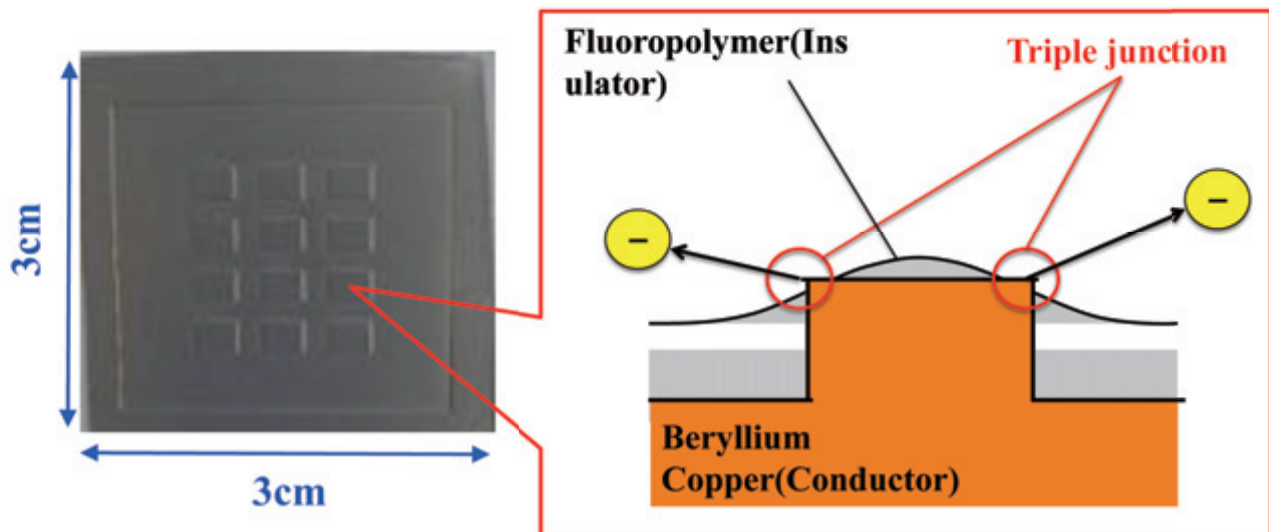


中国

44

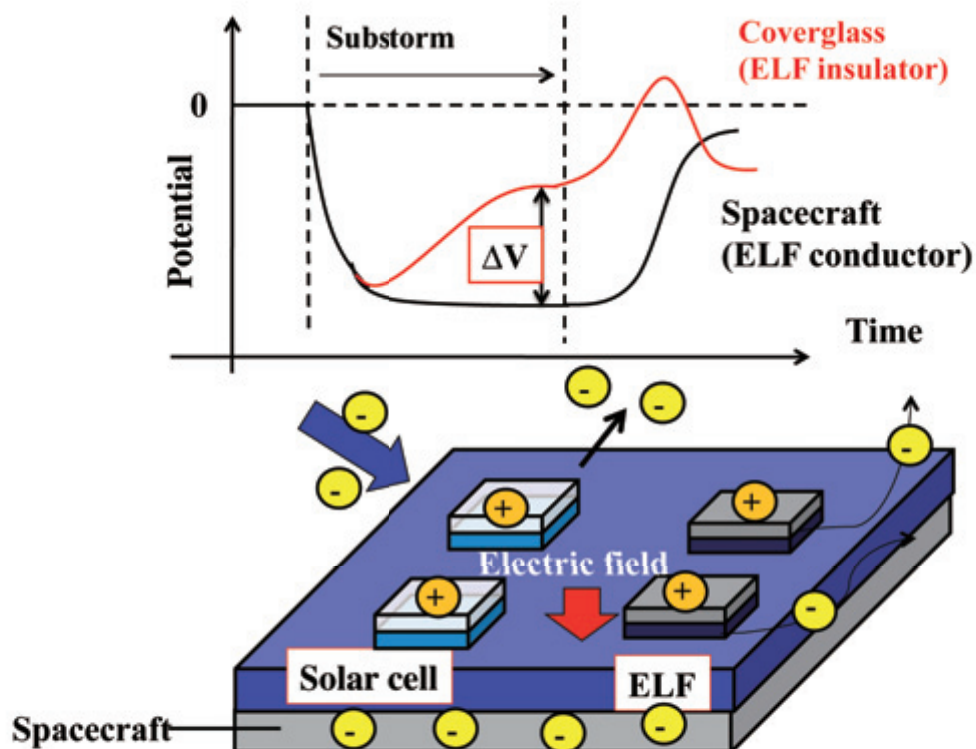
## 帯電放電抑制

- **ELF: Electron Emitting Film**



45

## Charging mitigation principle

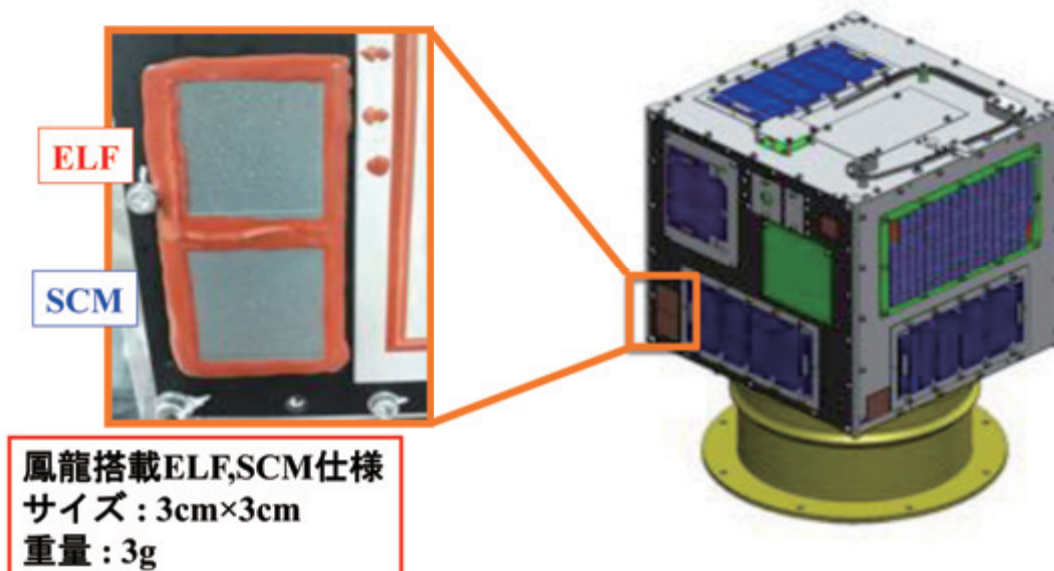


46





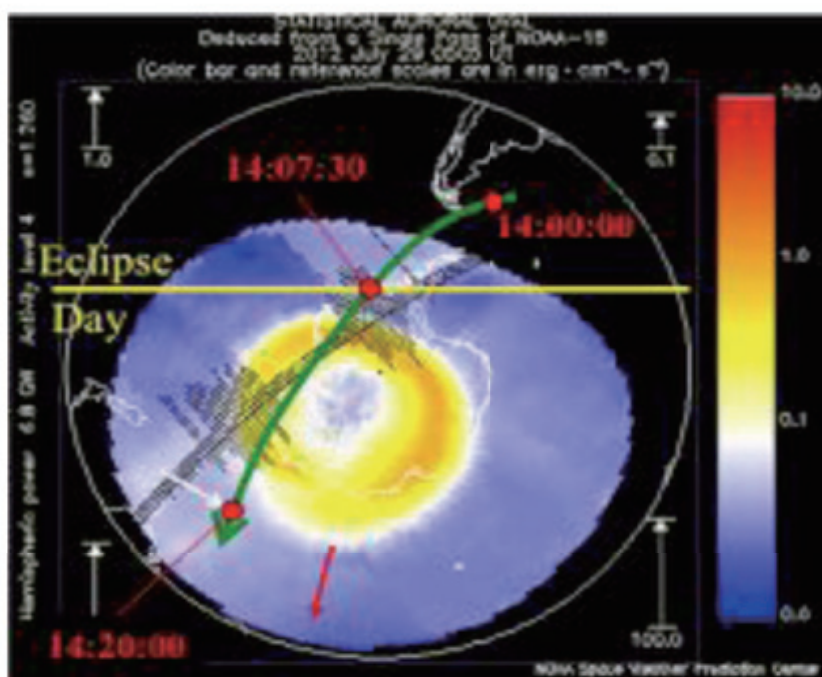
## HORYU 2



47

### In-orbit demonstration

## State of high-energy electron



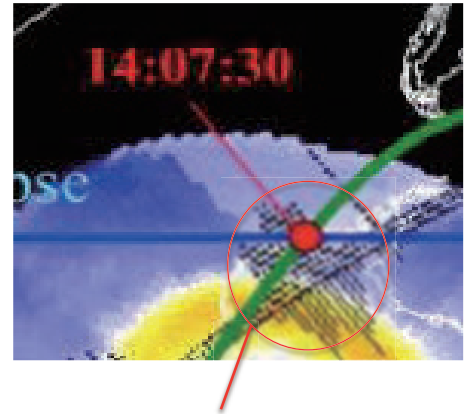
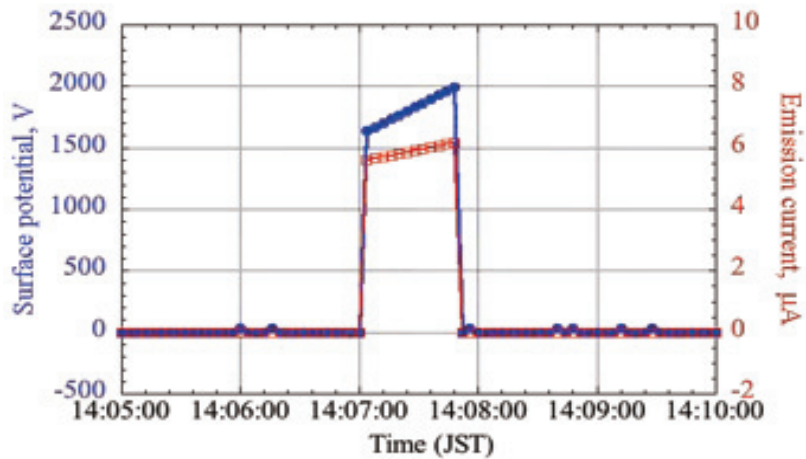
- Aurora strength
- Electron energy
- Position
- orbit
- Eclipse/day boundary

action time: 20min  
start time 14:00:00 JST  
end time 14:20:00 JST

48

## In-orbit demonstration

## Test results



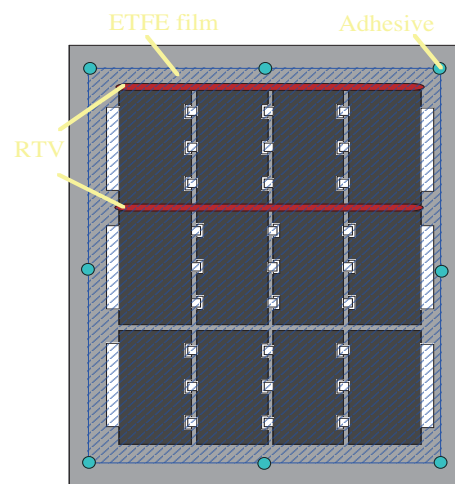
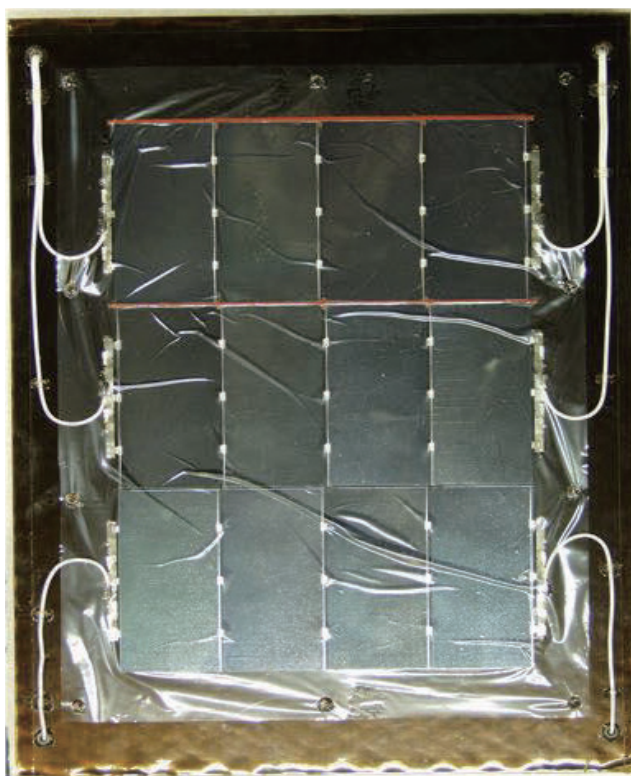
Emission of 6μA

Electron energy was very high

ELF operation in orbit was confirmed!

49

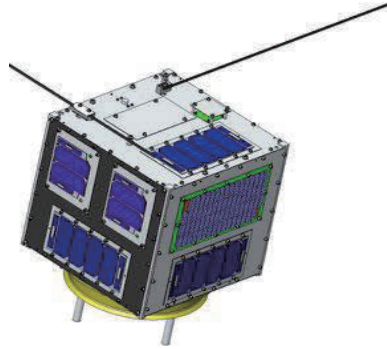
## Film coupon



Film thickness: 12.5μm

## Overview of HORYU-II and High Voltage Mission

### High Voltage Technology Demonstration Satellite ,HORYU-II



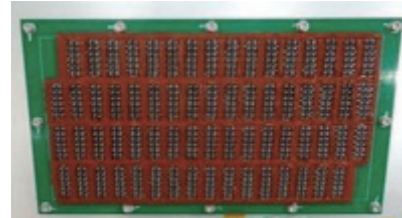
Horyu2

680km Sun-synchronous orbit

Nano-satellites are thus more suitable to higher risk missions



#### High Risk Mission



Solar arrays for generating high voltage

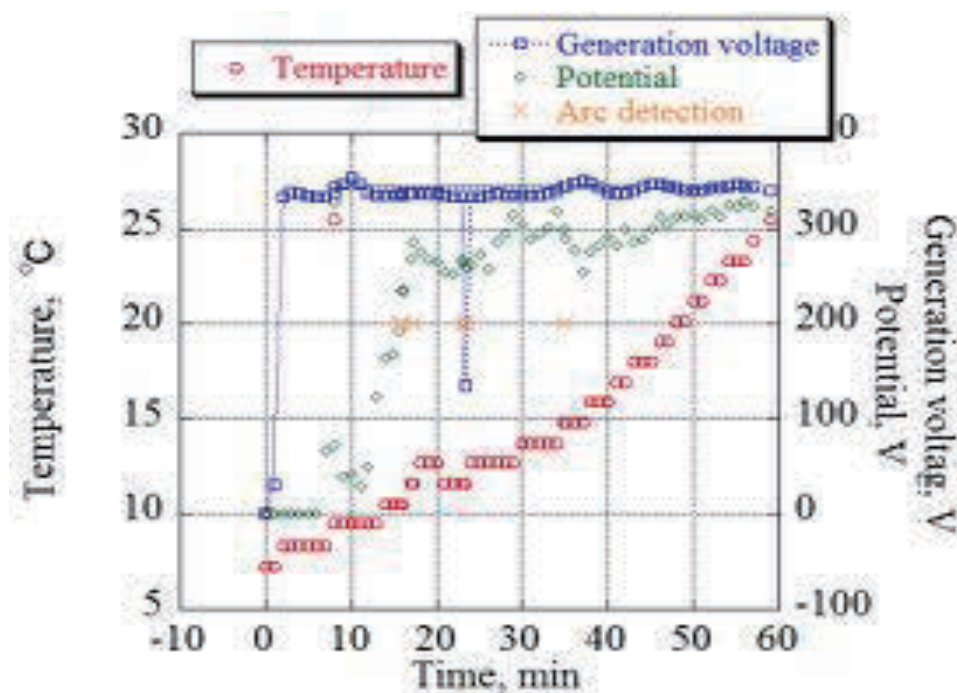


Solar arrays for mitigating to ESD

51

51

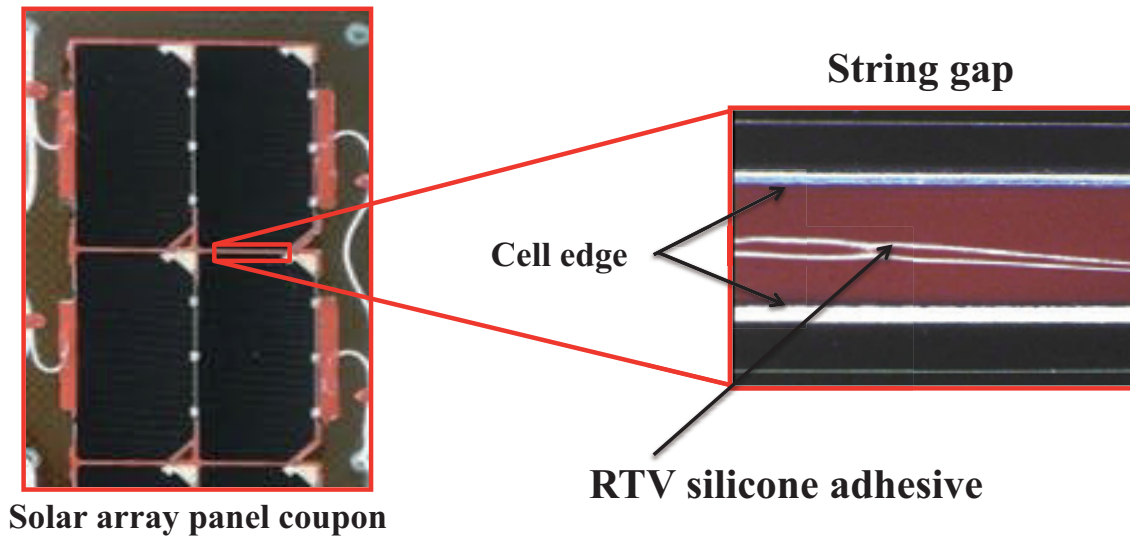
### Mode 3: TJ array arcing test mode



52



# Grouting



*Effect of aging on Discharge Tolerance  
of Grouted Solar Array Panels is unclear*

**Proton + Electron + Thermal cycling**

53

## Visual examination result



● :Crack

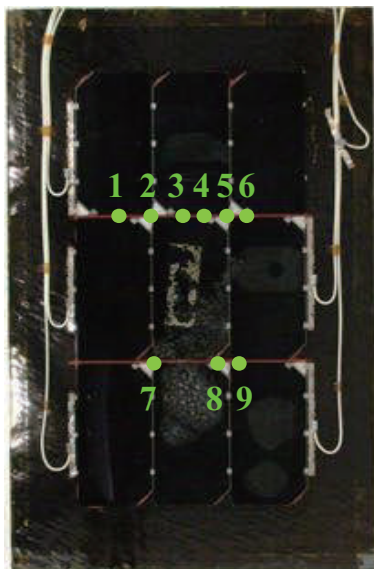
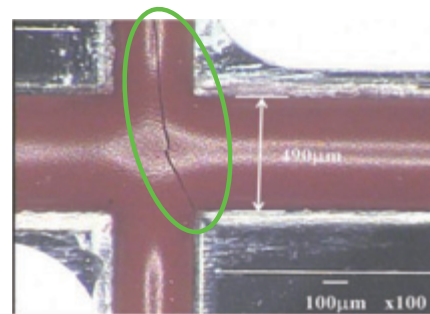
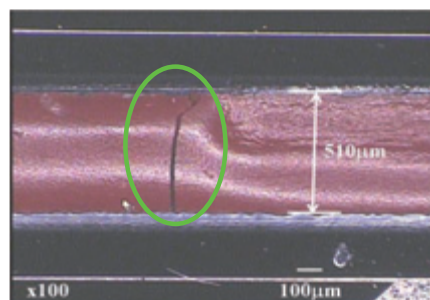


Photo of test coupon after simulated  
space environment test



Microscope picture of crack 2

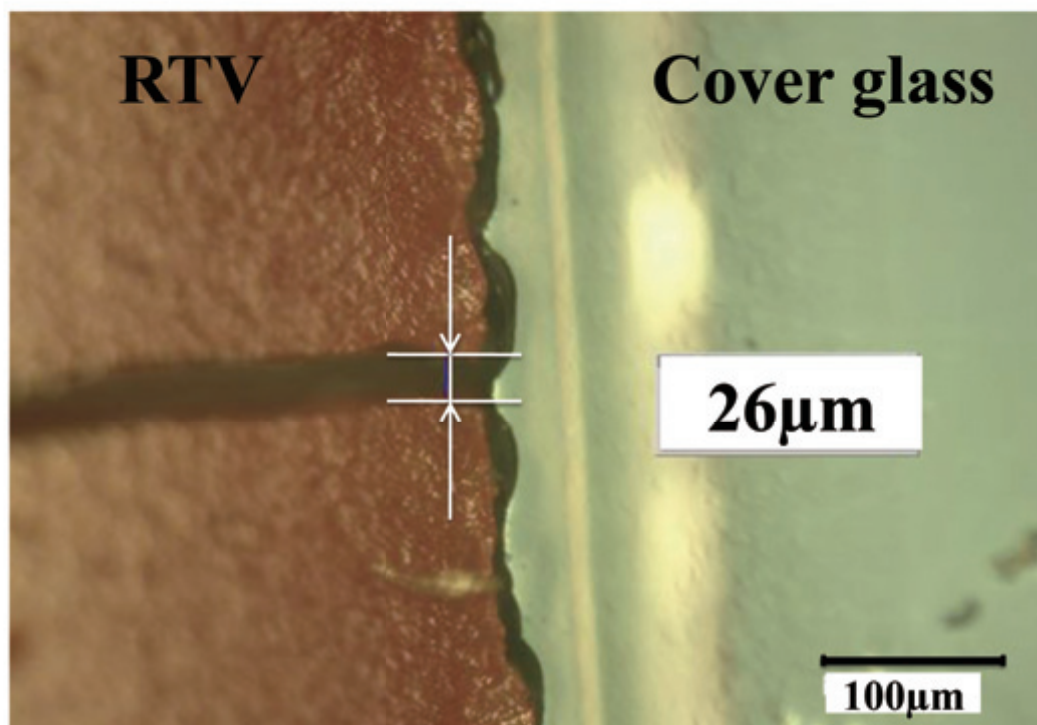


Microscope picture of crack 4

**Cracks were founded at the 9 points in total.**

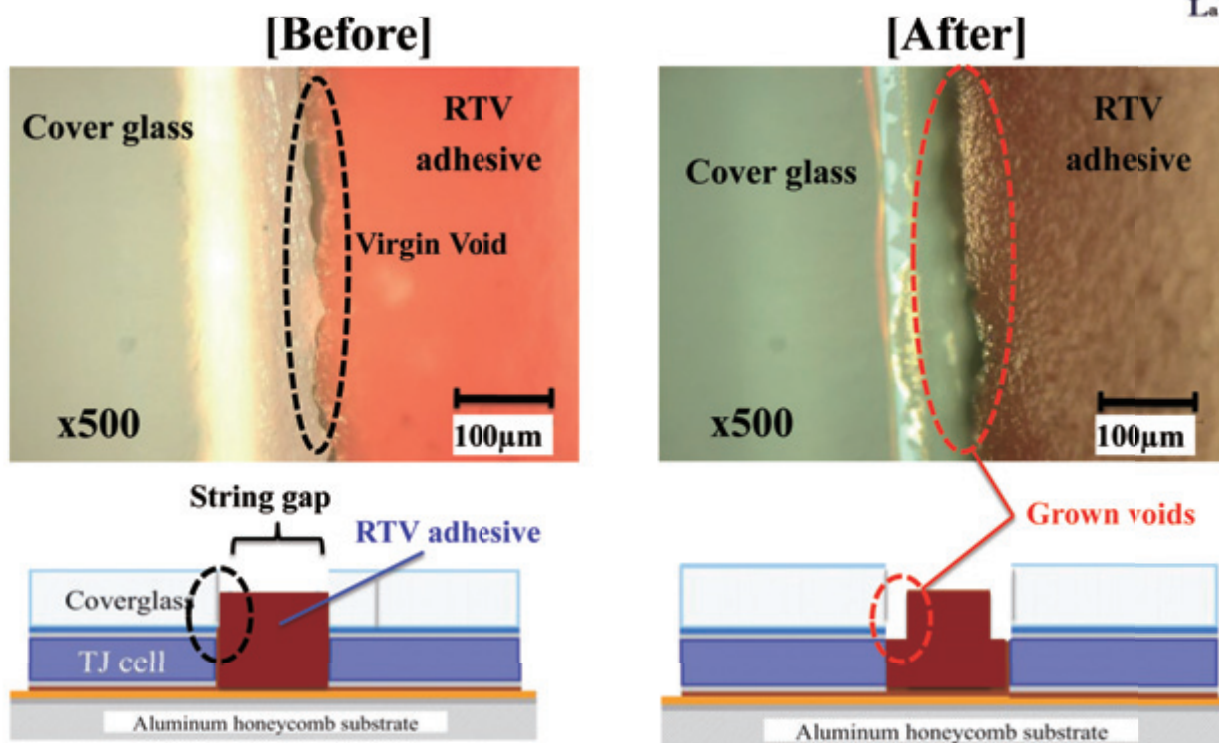
54

## Width of crack



55

## Visual examination result (2/2)



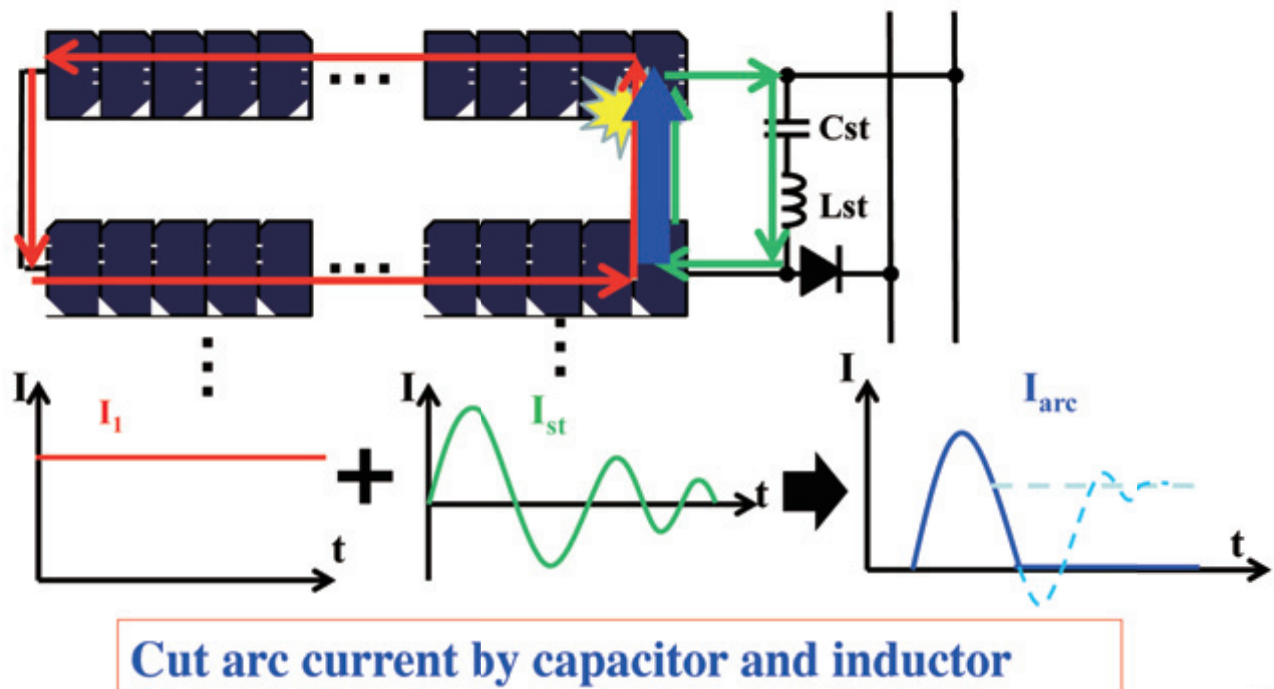
**Growth of voids were found  
at the interfaces between Cover glass and RTV-adhesive.**

56



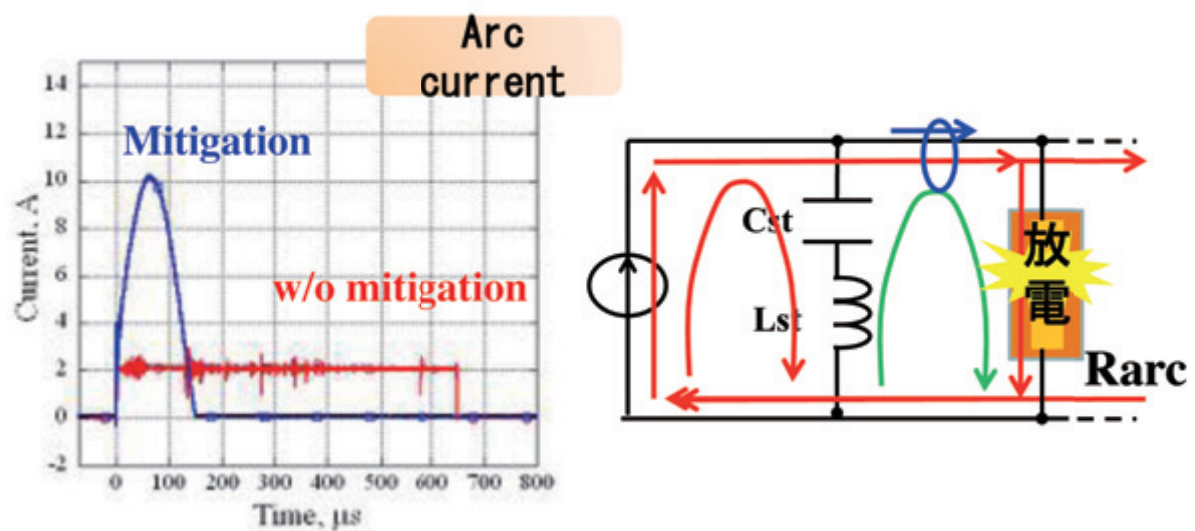


## Sustained arc mitigation method



57

## With mitigation method



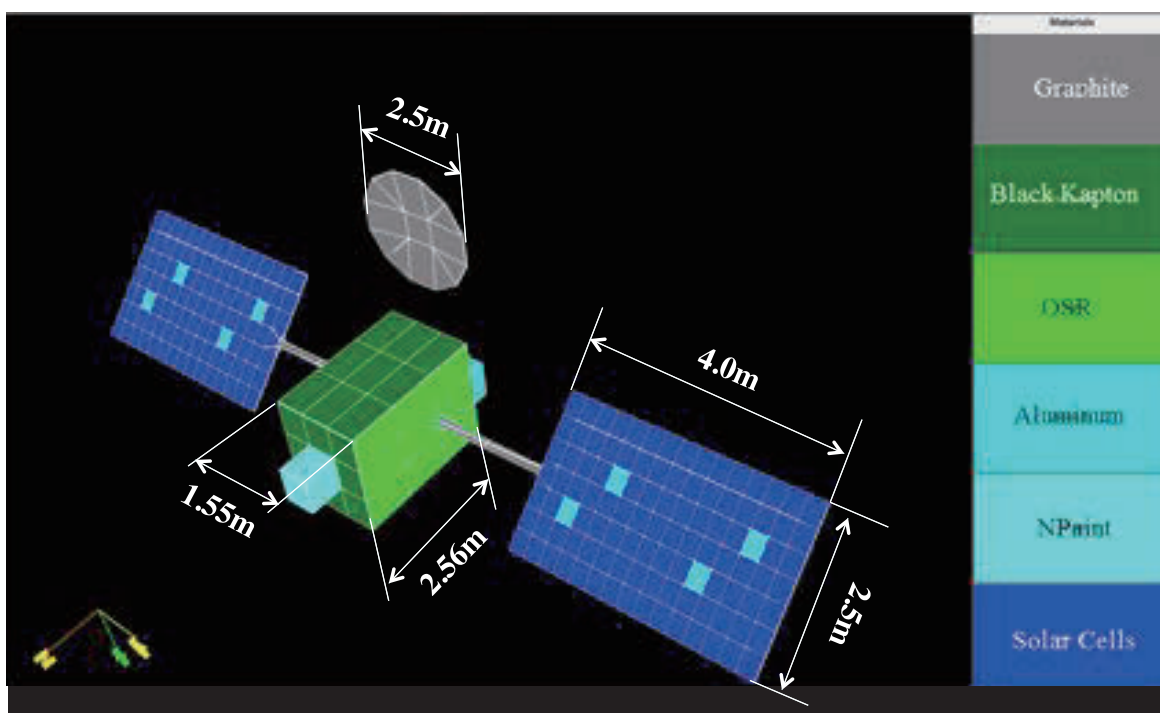
## WD19923 Spacecraft charging potential estimation in the worst case environments



- **Background**
  - No criteria to estimate worst case of spacecraft charging in each space environment
  - Worst charging potential should be tested in ESD ground testing (ISO-11221)
- **Main purpose**
  - Provide space plasma environments for worst case differential potential simulation
  - Provide how to estimate worst potential difference with simulation code

59

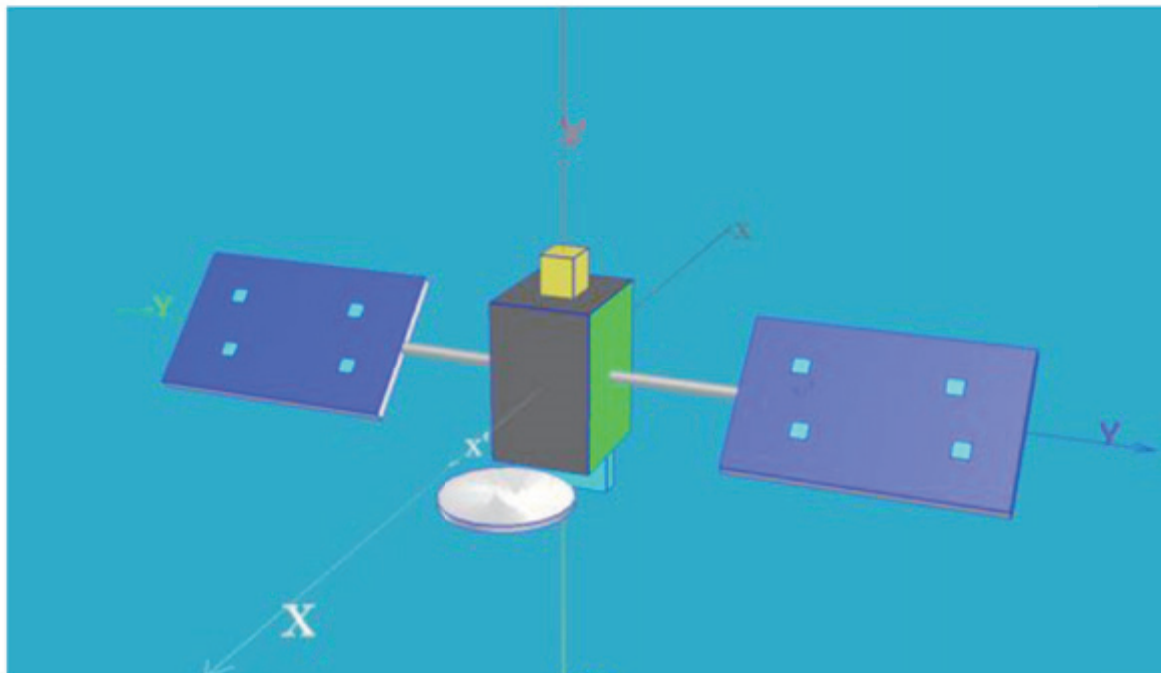
### Model: NASCAP-2k



60



## Model: MUSCAT

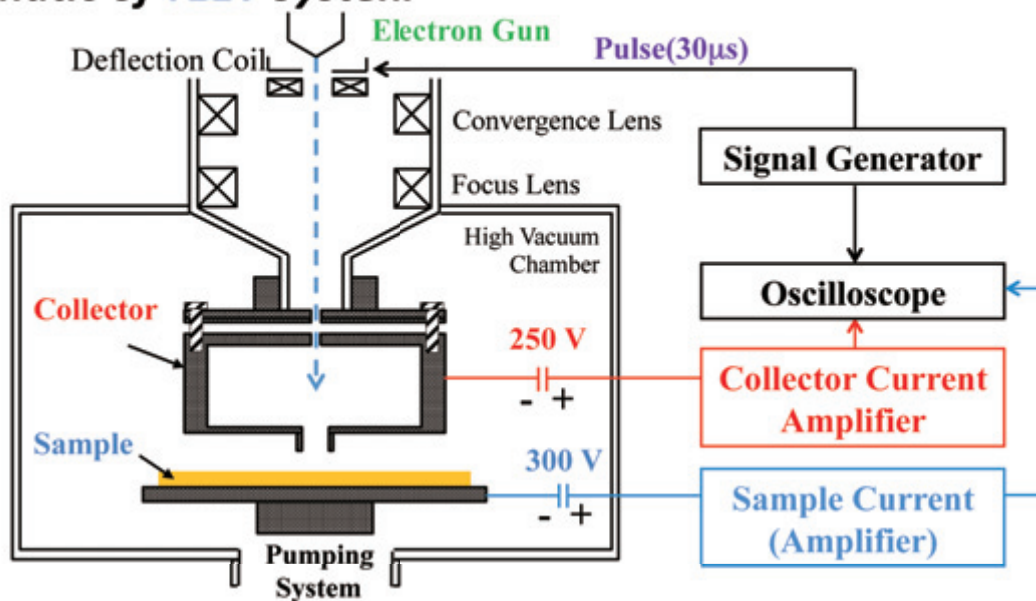


61

## 二次電子計測

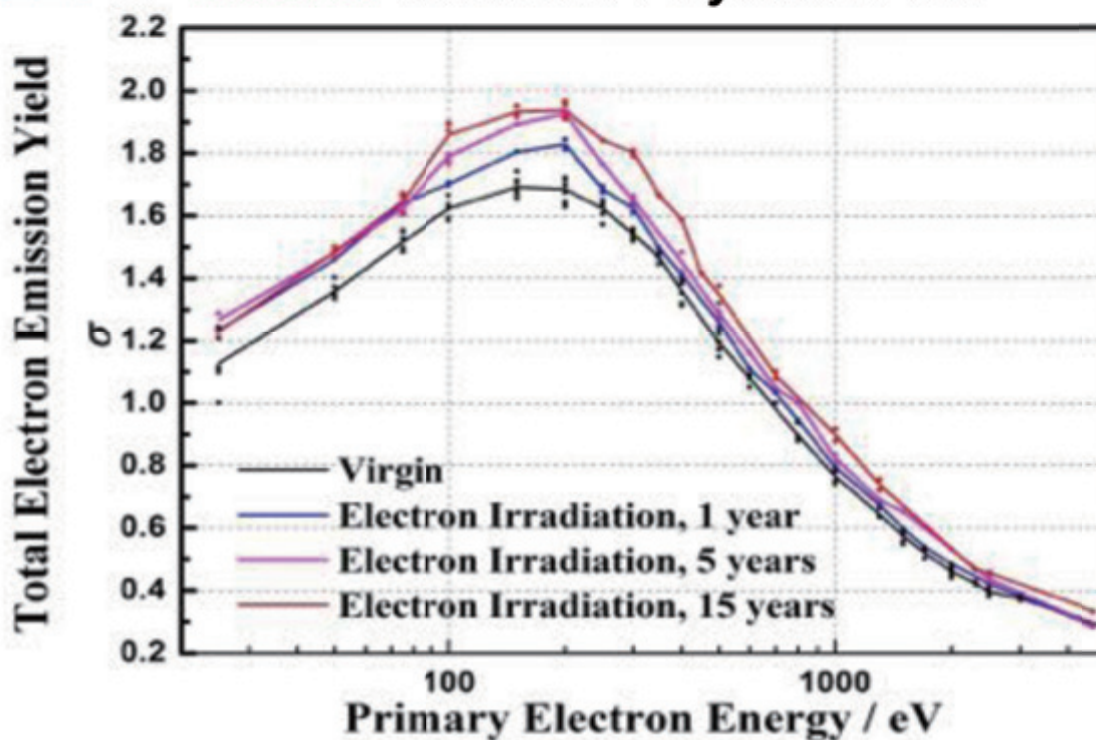


### Schematic of TEEY System



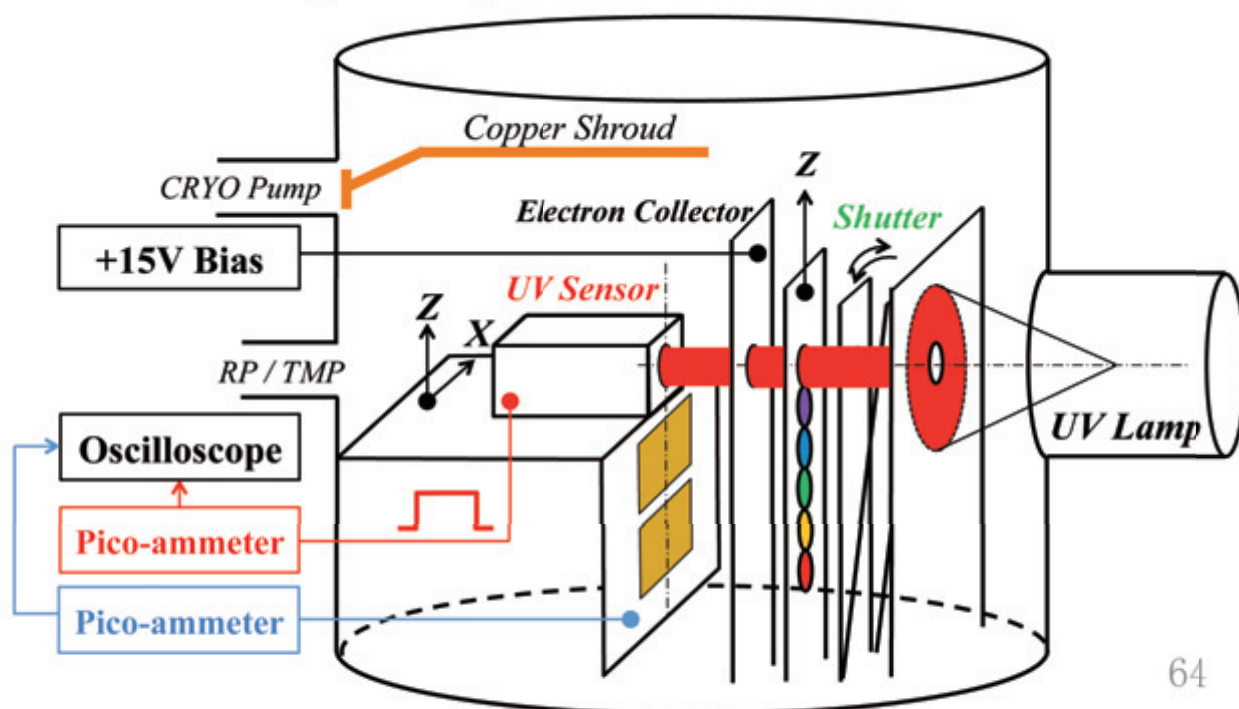
62

## TEEY of *Electron Irradiated Polyimide Film*



## 光電子計測

## Schematic of *PEY* System







## Kapton

Factors	TEEY		PEY
	yield	$E_{\max}$	yield
Ultraviolet	↑	—	↑
Atomic Oxygen	↓	↑	↑ ↓
Electron	↑	—	↓
Proton	—	—	↑

↑ Increase      ↓ Decrease      — Unchanged

65



66